Technical University of Denmark



## Principles and applications of a speckle-based wavefront sensor

Almoro, Percival; Hanson, Steen Grüner

Publication date: 2008

Document Version Publisher's PDF, also known as Version of record

Link back to DTU Orbit

*Citation (APA):* Almoro, P., & Hanson, S. G. (2008). Principles and applications of a speckle-based wavefront sensor. Abstract from Danish Optical Society Annual Meeting 2008, Nyborg, Denmark.

## DTU Library

Technical Information Center of Denmark

## **General rights**

Copyright and moral rights for the publications made accessible in the public portal are retained by the authors and/or other copyright owners and it is a condition of accessing publications that users recognise and abide by the legal requirements associated with these rights.

• Users may download and print one copy of any publication from the public portal for the purpose of private study or research.

- You may not further distribute the material or use it for any profit-making activity or commercial gain
- You may freely distribute the URL identifying the publication in the public portal

If you believe that this document breaches copyright please contact us providing details, and we will remove access to the work immediately and investigate your claim.

## Principles and applications of a speckle-based wavefront sensor

Percival F. Almoro\* and Steen G. Hanson Danish Technical University Fotonik, Department of Photonics Engineering, Roskilde 4000, DK \*percival.almoro@risoe.dk

The motivation for this study is to carry-out interferometric applications using phase retrieval which affords a simple setup. The wavefront sensor has 3 components: 1) diffuser, 2) speckle patterns, and a 3) phase retrieval algorithm. A coherent test wavefront incident on a diffuser facilitates the formation of a speckle field. The sampled speckle patterns are input in a phase retrieval algorithm to reconstruct and compare test wavefronts. In this presentation, basic principles of the algorithm and applications of the technique in deformation analysis and angular displacement measurements are presented.

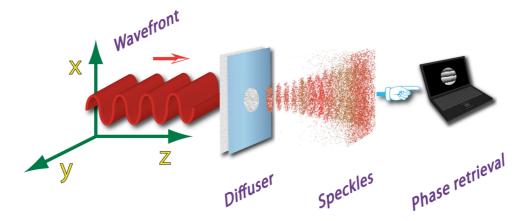


Fig. 1. Setup. A test wavefront incident on a phase diffuser generates a volume speckle field. Axially-displaced speckle intensity measurements are input in an algorithm based on the wave propagation equation.

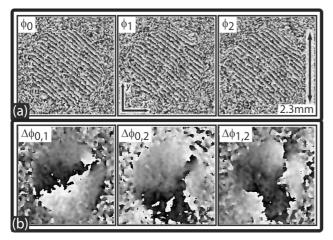


Fig. 2. Surface deformation analysis. (a) Retrieved phases for various deformation states. (b) Phase differences.

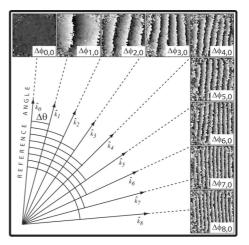


Fig. 3. Angular displacement measurement. Differences of retrieved phases for planar wavefronts with increasing angular displacements.